

<b>Notice of References Cited</b>	Application/Control No. 10/816,175	Applicant(s)/Patent Under Reexamination KENEN ET AL.	
	Examiner Martin Jeriko P. San Juan	Art Unit 2109	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,694,471	12-1997	Chen et al.	705/76
*	B	US-2001/0037455 A1	11-2001	Lawandy et al.	713/176
*	C	US-6,260,029 B1	07-2001	Critelli, Michael J.	705/408
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO/2001/095249 A2	12-2001	United Kingdom	Hudson et al.	G06K 19/00
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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